



Title of Change:	Release of T2000 tester platform for products NCV78763 (currently tested on Microflex).
Proposed Changed Material First Ship Date:	19 June 2018 <i>or earlier after customer approval</i>
Current Material Last Order Date:	15 July 2018 or earlier after customer approval Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.
Current Material Last Delivery Date:	15 July 2018 or earlier after customer approval The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory.
Product Category:	Active components – Integrated circuits
Contact information	Contact your local ON Semiconductor Sales Office, your Customer Quality Interface or <xavier.vanesch@onsemi.com>
Samples	No samples foreseen, unless requested by the customer. Contact your local ON Semiconductor Sales Office to place sample order. Sample requests are to be submitted no later than 45 days after publication of this change notification.
Sample Availability Date:	Not Applicable. No samples foreseen, unless requested by the customer.
PPAP Availability Date:	Not Applicable. No PPAP update foreseen.
Additional Reliability Data	Contact your local ON Semiconductor Sales Office, your Customer Quality Interface or <xavier.vanesch@onsemi.com>
Type of Notification	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change or earlier upon customer approval. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.
Change Category:	Type of Change
Equipment	Change in final test equipment type that uses a different technology
Description and Purpose:	
Release of a second tester platform, T2000, for Final Test and QC to improve Test Capacity and Load Balancing	
No impact on the product itself (form, fit, function and reliability)	
Reason / Motivation for Change:	Improved Test Capacity and Load Balancing
Anticipated impact on fit, form, function, reliability, product safety or manufacturability	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded. No anticipated impacts.
Sites Affected:	
☒ All site(s) ☐ not applicable ☐ ON Semiconductor site(s) : ☐ External Foundry/Subcon site(s)	



Marking of Parts/ Traceability of Change:	No change in marking or part number. Affected products will be identified with date code. First date code after the implementation of the change will be given to the customer, upon request
Reliability Data Summary: Not applicable. No change of material.	
Electrical Characteristic Summary: QC ambient correlation data between the source tester (Micro Flex) and the target tester (T2000) is provided in a separate qualification report together with the Final PCN "L763_uflex to T2000_Device_Test_Qualification_Report_PCN". 0L763 is the internal ONSEMI naming for the NCV78763 The same correlation procedure is used as in previous PCN's covering the release of additional tester platforms Two correlation units were datalogged in loop test at least 30 times on Reference tester uFlex37 in ON Oudenaarde . The test was done at 41°C , using QCA -mode of the test program. The same procedure was followed to obtain correlation data on Target tester t2k-02 in ON Oudenaarde upon transfer of the Device Test qualification package, using the same correlation units. Full parametric correlation was performed and for every test the shift was evaluated as follows: $\begin{aligned} \sigma_{\text{mean}} &= \text{abs}(\text{mean}(\text{ref}) - \text{mean}(\text{target})) \\ \sigma_{\text{sigma}} &= 0 && \text{if } \sigma(\text{target}) < \sigma(\text{ref}) \\ \sigma_{\text{sigma}} &= \sigma(\text{target}) - \sigma(\text{ref}) && \text{if } \sigma(\text{target}) > \sigma(\text{ref}) \end{aligned}$ $\text{shift} = \sigma_{\text{mean}} + 4 * \sigma_{\text{sigma}}$ If $\text{shift} < \max(5\% \text{ specwidth}, 6 * \sigma(\text{ref}))$ then correlation is OK for this test, else correlation is NOK for this test <i>Any parameter that exceeds the allowable shift is independently analyzed and explained.</i> Conclusion: 0L763-001 can be released for Device Test production testing on Advantest T2000. Note: Test Qualification Report is attached. <i>To access file attachments on pdf copy of PCN, please be guided by the steps below:</i> 1. Download pdf copy of the PCN to your computer 2. Open the downloaded pdf copy of the PCN 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field 4. Then click on the attached file/s	

**List of Affected Standard Parts:**

Current Part Number	New Part Number	Qualification Vehicle
NCV78763DQ0R2G	NCV78763DQ0R2G	NCV78763DQ0R2G
NCV78763DQ6R2G	NCV78763DQ6R2G	
NCV78763DQ0AR2G	NCV78763DQ0AR2G	
NCV78763DQ6AR2G	NCV78763DQ6AR2G	